## General Description

The MIC4223/MIC4224/MIC4225 are a family of a dual 4A, High-Speed, Low-side MOSFET drivers with logic-level driver enables. The devices are fabricated on Micrel's Bipolar/CMOS/DMOS (BCD) process and operate from a 4.5 V to 18 V supply voltage. The devices parallel Bipolar and CMOS output stage architecture provides high-current throughout the MOSFETs Miller Region allowing the driver to sink and source 4A of peak current from a 12 V supply and quickly charge and discharge a 2000pF load capacitance in under 15ns, while allowing the outputs to swing within 0.3 V of $\mathrm{V}_{\mathrm{DD}}$ and 0.16 V of ground.
The MIC4223/MIC4224/MIC4225 driver and enable inputs feature TTL and CMOS logic-level thresholds which are independent of supply voltage. Each driver features a dedicated active-high enable input which is internally pulled high to $V_{D D}$ through $100 \mathrm{k} \Omega$, allowing the pins to be left unconnected if it is not required to disable the driver outputs. The driver inputs have been designed to protect against ground bounce and are protected to withstand -5 V of voltage swing at -40 mA . Driver outputs are also protected to withstand 500 mA of reverse current.
The MIC4223/MIC4224/MIC4225 are available in three configurations using industry standard pin out; dual inverting (MIC4223), dual non-inverting (MIC4224) and complimentary (MIC4225). They are available in 8-pin SOIC and thermally enhanced e-PAD 8-pin MSOP and support operating junction temperatures from $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$.

## Applications

- High-Efficiency MOSFET switching
- Switch mode power supplies
- DC-to-DC converters
- Motor and solenoid drivers
- Clock and line drivers
- Synchronous rectifiers
- Pulse transformer drive
- Class D switching amplifiers


## Features

- 4.5 V to 18 V supply voltage operating range
- High peak source/sink current
$- \pm 3 \mathrm{~A}$ at $\mathrm{V}_{\mathrm{DD}}=8 \mathrm{~V}$
$- \pm 4 \mathrm{~A}$ at $\mathrm{V}_{\mathrm{DD}}=12 \mathrm{~V}$
- 15ns/15ns Rise and Fall times with 2000pF load
- 25ns/35ns (Rising/Falling) input propagation delay
- 20ns/45ns (Rising/Falling) enable propagation delay
- Active-high driver enable inputs with $100 \mathrm{k} \Omega$ pull-ups
- CMOS and TTL logic input and enable thresholds independent of supply voltage
- Driver input protection to -5 V at -40 mA
- Output Latch-up protection to $>500 \mathrm{~mA}$ reverse current
- Industry standard pin out with two package options
- ePAD MSOP-8 ( $\left.\theta_{\mathrm{JA}}=60^{\circ} \mathrm{C} / \mathrm{W}\right)$
- 8-pin SOIC $\left(\theta_{\mathrm{JA}}=120^{\circ} \mathrm{C} / \mathrm{W}\right)$
- Available in dual-inverting (MIC4223), dual noninverting (MIC4224) and complementary (MIC4225)
- Dual output drive by paralleling channels
- $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ operating junction temperature range


## Block Diagram



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## Ordering Information

| Part Number | Configuration | Junction Temp. Range | Package | Lead Finish |
| :--- | :---: | :---: | :--- | :---: |
| MIC4223YM | Dual Inverting | $-40^{\circ}$ to $+125^{\circ} \mathrm{C}$ | 8-pin SOIC | Pb-Free |
| MIC4223YMME | Dual Inverting | $-40^{\circ}$ to $+125^{\circ} \mathrm{C}$ | 8-pin EPAD-MSOP | Pb-Free |
| MIC4224YM | Dual Non-inverting | $-40^{\circ}$ to $+125^{\circ} \mathrm{C}$ | 8-pin SOIC | Pb-Free |
| MIC4224YMME | Dual Non-inverting | $-40^{\circ}$ to $+125^{\circ} \mathrm{C}$ | 8 8-pin EPAD-MSOP | Pb-Free |
| MIC4225YM | Inverting + Non-inverting | $-40^{\circ}$ to $+125^{\circ} \mathrm{C}$ | 8-pin SOIC | Pb-Free |
| MIC4225YMME | Inverting + Non-inverting | $-40^{\circ}$ to $+125^{\circ} \mathrm{C}$ | 8-pin EPAD-MSOP | Pb-Free |

## Pin Configuration



## Pin Description

| Pin Number | Pin Name | Pin Function |
| :---: | :---: | :--- |
| 1 | ENA | Enable pin for output A. TTL/CMOS-compatible logic input. A logic-level high enables the <br> device. An internal pull-up enables the part if pin is open. A logic-level low disables the device <br> and the output will be low regardless of the input state. |
| 2 | INA | Control Input A: TTL/CMOS-compatible logic input. Connect to V VD or ground if not used and <br> connect ENA to ground to disable driver A. |
| 3 | GND | Ground |
| 4 | INB | Control Input B: TTL/CMOS compatible logic input. Connect to V VD or ground if not used and <br> connect ENB to ground to disable driver B. |
| 5 | OUTB | Output B: Parallel Bipolar/CMOS output. |
| 6 | VDD | Voltage Supply Input: +4.5V to +18V |
| 7 | OUTA | Output A: Parallel Bipolar/CMOS output. |
| 8 | ENB | Enable pin for output B. TTL/CMOS-compatible logic input. A logic-level high enables the <br> device. An internal pull-up enables the part if pin is open. A logic-level low disables the device <br> and the output will be low regardless of the input state. |
| EP | GND | Exposed thermal pad for ePad MSOP package only (Not available on SOIC-8L package). <br> Connect to ground. Must make a full connection to the ground plane to maximize thermal <br> performance of the package. |

## Absolute Maximum Ratings ${ }^{(1)}$

Supply Voltage (VD)

| Input Voltage ( $\mathrm{V}_{\text {INA }}, \mathrm{V}_{\text {INB }}$ ) .............. $\mathrm{V}_{\mathrm{DD}}+0.3 \mathrm{~V}$ to GND - 5 V |  |
| :---: | :---: |
|  |  |
| Junction Temperature ( $\mathrm{T}_{\mathrm{J}}$ ) | $-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Storage Temperature | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Lead Temperature (10 sec | $300^{\circ} \mathrm{C}$ |
| ESD Rating. | $=2 \mathrm{kV}, \mathrm{MM}=200 \mathrm{~V}^{(3)}$ |

## Operating Ratings ${ }^{(2)}$

Supply Voltage ( $\mathrm{V}_{\mathrm{DD}}$ ).................................. +4.5 V to +18 V
Junction Temperature ( $\mathrm{T}_{\mathrm{J}}$ ) ...................... $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
Package Thermal Resistance
EPAD MSOP ( $\theta_{\mathrm{JA}}$ )
$60^{\circ} \mathrm{C} / \mathrm{W}$
SOIC ( $\theta_{\text {JA }}$ ) ........................................................ $120^{\circ} \mathrm{C} / \mathrm{W}$

## Electrical Characteristics

$4.5 \mathrm{~V} \leq \mathrm{V}_{\mathrm{DD}} \leq 18 \mathrm{~V} ; \mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF} . \mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, bold values indicate full operating junction temperature range, unless noted.

| Symbol | Parameter | Condition | Min | Typ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Input |  |  |  |  |  |  |
| $\mathrm{V}_{\text {IH }}$ | Logic 1 Input Voltage |  | 2.4 | 2.2 |  | V |
| $\mathrm{V}_{\text {IL }}$ | Logic 0 Input Voltage |  |  | 1.95 | 0.8 | V |
| Hysteresis |  |  |  | 0.25 |  | V |
| $\mathrm{I}_{\mathrm{N}}$ | Input Current | $0 \leq \mathrm{V}_{\mathrm{IN}} \leq \mathrm{V}_{\mathrm{DD}}$ | $\begin{gathered} -1 \\ -10 \end{gathered}$ |  | $\begin{gathered} 1 \\ 10 \end{gathered}$ | $\begin{aligned} & \mu \mathrm{A} \\ & \mu \mathrm{~A} \end{aligned}$ |
|  |  | $\mathrm{V}_{\text {IN }}=-5 \mathrm{~V}$ |  | -40 |  | mA |
| Output |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{OH}}$ | High Output Voltage | $\mathrm{l}_{\text {OUT }}=-10 \mathrm{~mA}, \mathrm{~V}_{\text {DD }}=18 \mathrm{~V}$ | VDD -0.45 |  |  | V |
| VoL | Low Output Voltage | $\mathrm{l}_{\text {OUT }}=10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{DD}}=18 \mathrm{~V}$ |  |  | 0.30 | V |
| RO | Output Resistance - Source <br> Output Resistance - Sink | $\begin{aligned} & \text { lout }=-10 \mathrm{~mA}, V_{D D}=18 \mathrm{~V} \\ & \text { lout }=10 \mathrm{~mA}, \mathrm{~V}_{\mathrm{DD}}=18 \mathrm{~V} \end{aligned}$ |  | $\begin{aligned} & 30 \\ & 16 \end{aligned}$ | $\begin{aligned} & 45 \\ & 30 \end{aligned}$ | $\Omega$ |
| IPK | Peak Output Current | $\mathrm{V}_{\mathrm{DD}}=8 \mathrm{~V}$ |  | $\pm 3$ |  | A |
|  |  | $\mathrm{V}_{\mathrm{DD}}=12 \mathrm{~V}$ |  | $\pm 4$ |  |  |
| 1 | Latch-Up Protection | Withstand reverse current |  | >500 |  | mA |
| Switching Time |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{R}}$ | Rise Time | Test Figure 1; $\mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF}$ |  | 15 | 40 | ns |
| $\mathrm{t}_{\mathrm{F}}$ | Fall Time | Test Figure 1; $\mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF}$ |  | 15 | 40 | ns |
| $t_{\text {D1 }}$ | Delay Time | Test Figure 1; $\mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF}$ |  | 25 | 45 | ns |
| $t_{\text {D2 }}$ | Delay Time | Test Figure 1; $\mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF}$ |  | 35 | 50 | ns |
| Enable (ENA, ENB) |  |  |  |  |  |  |
| VEN_H | High Level Enable Voltage | LO to HI transition | 2.4 | 1.9 |  | V |
| VEN_L | Low Level Enable Voltage | HI to LO transition |  | 1.55 | 0.8 | V |
| Hysteresis |  |  |  | 0.35 |  | V |
| $\mathrm{R}_{\mathrm{EN}}$ | Enable Impedance | $\mathrm{V}_{\mathrm{DD}}=18 \mathrm{~V}, \mathrm{~V}_{\mathrm{ENA}}=\mathrm{V}_{\mathrm{ENB}}=\mathrm{GND}$ |  | 100 |  | k $\Omega$ |
| $\mathrm{t}_{\mathrm{D} 3}$ | Propagation Delay Time | $\mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF}$ |  | 20 | 60 | ns |
| $\mathrm{t}_{\mathrm{D} 4}$ | Propagation Delay Time | $\mathrm{C}_{\mathrm{L}}=2000 \mathrm{pF}$ |  | 45 | 150 | ns |
| Power Supply |  |  |  |  |  |  |
| $\mathrm{I}_{\text {SH }}$ | Power Supply Current | $\mathrm{V}_{\text {INA }}=\mathrm{V}_{\text {INB }}=3.0 \mathrm{~V}, \mathrm{~V}_{\text {ENA }}=\mathrm{V}_{\text {ENB }}=$ open |  | 1.7 | 2.5 | mA |
| $\mathrm{I}_{\text {SL }}$ | Power Supply Current | $\mathrm{V}_{\text {INA }}=\mathrm{V}_{\text {INB }}=0.0 \mathrm{~V}, \mathrm{~V}_{\text {ENA }}=\mathrm{V}_{\text {ENB }}=$ open |  | 0.7 | 1.5 | mA |

Notes:

1. Exceeding the absolute maximum rating may damage the device.
2. The device is not guaranteed to function outside its operating rating.
3. Devices are ESD sensitive. Handling precautions recommended. Human body model, $1.5 \mathrm{k} \Omega$ in series with 100 pF .

## Test Circuit



Figure 1. Test Circuit

## Timing Diagram



Inverting Driver


Non-Inverting Driver


Enable to Output Timing Diagram

## Typical Characteristics

Conditions: $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.


Enable Threshold vs.
Temperature


IDD vs. Temperature
(Disabled)

$\mathrm{I}_{\mathrm{DD}}$ Vs. Frequency $\left(\mathrm{V}_{\mathrm{DD}}=5 \mathrm{~V}\right)$ Both Drivers Switching

$\mathrm{V}_{\mathrm{INA}}$, в Threshold vs.
Temperature

$\mathrm{I}_{\mathrm{DD}}$ vs. $\mathrm{V}_{\mathrm{DD}}$ (Disabled)


IDD vs. Temperature (Enabled)

$I_{D D}$ vs. Frequency ( $\mathrm{V}_{\mathrm{DD}}=5 \mathrm{~V}$ ) Both Drivers Switching


$I_{D D}$ vs. $V_{D D}$ (Enabled)

$I_{D D}$ vs. Temperature
(Switching)

$\mathrm{I}_{\mathrm{DD}}$ VS. Frequency $\left(\mathrm{V}_{\mathrm{DD}}=12 \mathrm{~V}\right)$ Both Drivers Switching


Conditions: $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\mathrm{I}_{\mathrm{DD}}$ vs. Frequency ( $\mathrm{V}_{\mathrm{DD}}=12 \mathrm{~V}$ ) Both Drivers Switching

$\mathrm{I}_{\mathrm{DD}}$ Vs. $\mathrm{V}_{\mathrm{DD}}\left(\mathrm{C}_{\mathrm{L}}=4.7 \mathrm{nF}\right)$ Both Drivers Switching


## Output Rise Time vs. $\mathrm{V}_{\mathrm{DD}}$



Propagation Delay ( $\mathrm{t}_{\mathrm{D} 1}$ )

$\mathrm{I}_{\mathrm{DD}} \mathrm{VS}$. $\mathrm{V}_{\mathrm{DD}}\left(\mathrm{C}_{\mathrm{L}}=2.2 \mathrm{nF}\right)$
Both Drivers Switching

$\mathrm{I}_{\mathrm{DD}}$ Vs. $\mathrm{V}_{\mathrm{DD}}\left(\mathrm{C}_{\mathrm{L}}=4.7 \mathrm{nF}\right)$ Both Drivers Switching


Output Fall Time vs. $\mathrm{V}_{\mathrm{DD}}$


Propagation Delay ( $t_{D 1}$ )
vs. $V_{D D}$

$I_{D D} \mathrm{VS} . \mathrm{V}_{\mathrm{DD}}\left(\mathrm{C}_{\mathrm{L}}=2.2 \mathrm{nF}\right)$
Both Drivers Switching


Output Rise Time vs. $\mathrm{V}_{\mathrm{DD}}$


Output Fall Time vs. $\mathrm{V}_{\mathrm{DD}}$


Propagation Delay ( $\mathrm{t}_{\mathrm{D} 2}$ )
vs. $V_{D D}$


Conditions: $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.


Output Rise Time vs. Temperature


Prop. Delay (Non-Inverting)
vs. Temperature


Output Source Resistance
vs. Temperature


Output Fall Time
vs. Temperature


Enable to Output Delay
( $t_{D 3}$ ) vs. Temperature


Output Sink Resistance vs. Temperature


Prop. Delay (Inverting)
vs. Temperature


Enable to Output Delay
( $\mathrm{t}_{\mathrm{D}}$ ) vs. Temperature


## Functional Diagram



## Logic Table

| Enables |  | Inputs |  | MIC4223 |  | MIC4224 |  | MIC4225 |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ENA | ENB | INA | INB | OUTA | OUTB | OUTA | OUTB | OUTA | OUTB |
| H | H | L | L | H | H | L | L | H | L |
| H | H | L | H | H | L | L | H | H | H |
| H | H | H | L | L | H | H | L | L | L |
| H | H | H | H | L | L | H | H | L | H |
| L | L | X | X | L | L | L | L | L | L |

## Block Diagram



## Functional Description

The MIC4223, MIC4224 and MIC4225 are a family of dual high speed, high current drivers. The drivers come in both inverting and non-inverting versions. Each driver has an enable pin that turns the output off (low) regardless of the input.
The MIC4223 is a dual inverting driver. The MIC4224 is a dual non-inverting driver and the MIC4225 contains an inverting and non-inverting driver.

## Enable

Each output has an independent enable pin that forces the output low when the enable pin is driven low. Each enable pin is internally pulled-up to $V_{D D}$. The outputs are enabled by default if the enable pin is left open. Pulling the enable pin low, below its threshold voltage, forces the output low. A fast propagation delay between the enable and output pins quickly disables the output, which is a requirement during a system fault condition.

## Input Stage

The driver input stage is high impedance, TTL-compatible input stage. The driver's input threshold voltage makes it compatible with TTL and CMOS devices that are powered from supply voltages between 3 V and $\mathrm{V}_{\mathrm{DD}}$. Hysteresis on the input pin improves noise immunity and prevents input signals with slow rise times from falsely triggering the output. The VDD pin current is slightly higher when the input voltage is above the high level threshold. See the Typical Characteristic graphs for additional information.
The input voltage signal may go up to -5 V below ground without damage to the driver or cause a latch up condition. Negative input voltages that are 0.7 V below ground or greater will increase propagation delay.

## Output Driver Section

A functional diagram of the driver output is shown in Figure 2. The output drive is a parallel combination of MOSFET and Bipolar transistor. For a given silicon area, a bipolar device has a lower on-resistance than an equivalent MOS device. It sources and sinks current more consistently as the voltage across it changes. The low drive impedance of the bipolar allows fast turn-on and turn-off of the external MOSFET. The driver's internal MOSFET gives the output near rail-to-rail drive capability. This ensures a low $\mathrm{R}_{\text {DSon }}$ for the external MOSFET as well as noise immunity from $\mathrm{dv} / \mathrm{dt}$ induced glitching.


Figure 2. Output Driver
The slew rate of the output is non-adjustable and depends only on the $V_{D D}$ voltage and how much capacitance is present at the OUTA, B pin. Changing the slew rate at the driver's input pin will not affect the output rise or fall times. The slew rate at the MOSFET gate can be adjusted by adding a resistor between the MOSFET gate and the driver output.

## Application Information

## Power Dissipation Considerations

Power dissipation in the driver can be separated into two areas:

Output driver stage dissipation
Quiescent current dissipation used to supply the internal logic and control functions.

## Output Driver Stage Power Dissipation

Power dissipation in the driver's output stage is mainly caused by charging and discharging the gate to source and gate to drain capacitance of the external MOSFET. Figure 3 shows a simplified circuit of the MIC4223 driving an external MOSFET.


Figure 3. Functional MOSFET/Driver Diagram

## Dissipation Caused by Switching the External MOSFET

Energy from capacitor $C_{V D D}$ is used to charge up the input capacitance of the MOSFET ( $\mathrm{C}_{\mathrm{GD}}$ and $\mathrm{C}_{\mathrm{GS}}$ ). The energy delivered to the MOSFET is dissipated in the upper driver MOSFET and Bipolar impedances. The effective capacitance of $C_{G D}$ and $C_{G S}$ is difficult to calculate since they vary non-linearly with $\mathrm{I}_{\mathrm{D}}, \mathrm{V}_{\mathrm{GS}}$, and $\mathrm{V}_{\mathrm{DS}}$. Fortunately, most power MOSFET specifications include a typical graph of total gate charge vs. $\mathrm{V}_{\mathrm{Gs}}$. Figure 4 shows a typical MOSFET gate charge curve. The graph illustrates that for a gate voltage of 10V, the MOSFET requires about $23.5 n C$ of charge.


Figure 4. MOSFET Gate Charge vs. $\mathrm{V}_{\mathrm{GS}}$
The energy dissipated during turn-on is calculated as:
$E=\frac{1}{2} \times C_{i s s} \times V_{G S}{ }^{2}$
where $\mathrm{C}_{\text {iss }}$ is the MOSFET's total gate capacitance
but:
$\mathrm{Q}=\mathrm{C} \times \mathrm{V}$
So
$\mathrm{E}=1 / 2 \times \mathrm{Q}_{\mathrm{G}} \times V_{G S}$
An equivalent amount of energy is dissipated in the driver's sink circuit when the MOSFET turns off. The total energy and power dissipated by the drive components is:
$E_{\text {DRIVER }}=Q_{G} \times V_{G S}$
and
$P_{\text {DRIVER }}=Q_{G} \times V_{G S} \times f_{S}$
Where:
$E_{\text {DRIVER }}$ is the energy dissipated per switching cycle
$P_{\text {DRIVER }}$ is the power dissipated by switching the MOSFET on and off
$\mathrm{Q}_{\mathrm{G}}$ is the total Gate charge at $\mathrm{V}_{\mathrm{GS}}$
$V_{G S}$ is the MOSFETs Gate to Source voltage
$f_{S}$ is the switching frequency of the Gate drive circuit

## Quiescent Current Power Dissipation

Quiescent current powers the internal logic, level shifting circuitry and bias for the output drivers. This current is proportional to operating frequency and $\mathrm{V}_{\mathrm{DD}}$ voltage. The typical characteristic graphs show how supply current varies with switching frequency and supply voltage.
The power dissipated by the driver's quiescent current is:

$$
\text { Pdiss }_{\text {quiescent }}=V_{D D} \times I_{D D}
$$

## Total Power Dissipation and Thermal Considerations

Total package power dissipation equals the power dissipation of each driver caused by driving the external MOSFETs plus the supply current.

$$
\text { Pdiss }_{\text {TOTAL }}=\text { Pdiss }_{\text {quiescent }}+\text { Pdriver }_{A}+\text { Pdriver }_{B}
$$

The die temperature may be calculated once the total power dissipation is known.

$$
T_{J}=T_{A}+\text { Pdiss }_{T O T A L} \times \theta_{J A}
$$

Where:
$T_{A}$ is the Maximum ambient temperature
$\mathrm{T}_{\mathrm{J}}$ is the junction temperature $\left({ }^{\circ} \mathrm{C}\right)$
Pdiss $_{\text {total }}$ is the power dissipation of the Driver
$\theta_{\mathrm{JA}}$ is the thermal resistance from junction-toambient air ( ${ }^{\circ} \mathrm{C} / \mathrm{W}$ )
The following graphs help determine the maximum gate charge that can be driven with respect to switching frequency, supply voltage and ambient temperature.
Figure 5a shows the power dissipation in the driver for different values of gate charge with $\mathrm{V}_{\mathrm{DD}}=5 \mathrm{~V}$. Figure 5 b shows the power dissipation at $\mathrm{V}_{\mathrm{DD}}=12 \mathrm{~V}$. Figure 5 c show the maximum power dissipation for a given ambient temperature for the SOIC and ePAD MSOP packages.
The maximum operating frequency of the driver may be limited by the maximum power dissipation of the driver package.


Figure 5a. PDiss vs. $Q_{G}$ and $f_{S}$ for $V_{D D}=5 V$


Figure 5b. PDISs vs. $Q_{G}$ and $f_{s}$ for $V_{D D}=12 V$

## Maximum Power Dissipation



Figure 5c. Maximum P ${ }_{\text {DIss }}$ vs. Ambient Temperature

## Bypass Capacitor Selection

Bypass capacitors are required for proper operation by supplying the charge necessary to drive the external MOSFETs as well as minimize the voltage ripple on the supply pins.
Ceramic capacitors are recommended because of their low impedance and small size. Z5U type ceramic capacitor dielectrics are not recommended due to the large change in capacitance over temperature and voltage. Manufacturer specifications should be checked to insure voltage and temperature do not reduce the capacitance below the value needed. A minimum value of $1 \mu \mathrm{~F}$ is required regardless of the MOSFETs being driven. Larger MOSFETs, with their higher input capacitance may require larger decoupling capacitance values for proper operation. The voltage rating of the capacitors depends on the supply voltage, ambient temperature and the voltage derating used for reliability.
Placement of the decoupling capacitors is critical. The bypass capacitor for $V_{D D}$ should be placed as close as possible between the VDD and GND pins. The etch connections must be short, wide and direct. The use of a ground plane to minimize connection impedance is recommended. Multiple vias insure a low inductance path and help with power dissipation. Refer to the section on layout and component placement for more information.

## Grounding, Component Placement and Circuit Layout

Nanosecond switching speeds and ampere peak currents in and around the MOSFET driver necessitate proper placement and trace routing of all components. Improper placement may cause degraded noise immunity, false switching and excessive ringing.
Figure 6 shows the critical current paths when the driver outputs go high and turn on the external MOSFETs. It also helps demonstrate the need for a low impedance ground plane. Charge needed to turn-on the MOSFET gates comes from the decoupling capacitors $\mathrm{C}_{\text {vDD }}$. Current in the gate driver flows from $\mathrm{C}_{\text {VDD }}$ through the internal driver, into the MOSFET gate and out the Source. The return connection back to the decoupling capacitor is made through the ground plane. Any inductance or resistance in the ground return path causes a voltage spike or ringing to appear on the source of the MOSFET. This voltage works against the gate drive voltage and can either slow down or turn off the MOSFET during the period where it should be turned on.


Figure 6. Driver Turn-On Current Path
Figure 7 shows the critical current paths when the driver outputs go low and turn off the external MOSFETs. Short, low impedance connections are important during turn-off for the same reasons given in the turn-on explanation. Current from the $V_{D D}$ supply replenishes charge in the decoupling capacitor, C CVDD.


Figure 7. Driver Turn-Off Current Path
The following circuit guidelines should be adhered to for optimum circuit performance:
The $V_{D D}$ bypass capacitor must be placed close to the VDD and ground pins. It is critical that the etch length between the decoupling capacitor and the VDD and GND pins be minimized to reduce pin inductance. Multiple vias in parallel help minimize inductance in the ground and $V_{D D}$ paths.
A ground plane is recommended to minimize parasitic inductance and impedance of the return paths. The MIC4223 family of drivers is capable of high peak currents and very fast transition times. Any impedance between the driver, the decoupling capacitors and the external MOSFET will degrade the performance of the circuit.
Trace out the high di/dt and dv/dt paths, as shown in Figures 6 and 7 and minimize etch length and loop area for these connections. Minimizing these parameters decreases the parasitic inductance and the radiated EMI generated by fast rise and fall times.

## Evaluation Board Schematic (SOIC)



## Bill of Materials (SOIC)

| Item | Part Number | Manufacturer | Description | Qty. |
| :---: | :---: | :---: | :---: | :---: |
| C1 | VJ0603Y104KXXAT | Vishay ${ }^{(1)}$ | $0.1 \mu \mathrm{~F} / 25 \mathrm{~V}$, X7R Ceramic Capacitor, Size 0603 | 1 |
| $\begin{aligned} & \text { C2, C7 } \\ & \text { or } \\ & \text { or } \end{aligned}$ | C1608X5R1E105M | TDK ${ }^{(2)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}$, X5R, Ceramic Capacitor, Size 0603 | 2 |
|  | 06033D105MAT | AVX ${ }^{(3)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}$, X5R, Ceramic Capacitor, Size 0603 | 2 |
|  | GRM188R61E105KA93 | MuRata ${ }^{(4)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}, \mathrm{X} 5 \mathrm{R}$, Ceramic Capacitor, Size 0603 | 2 |
| $\begin{aligned} & \text { C4, C5 } \\ & \text { or } \\ & \text { or } \end{aligned}$ | C3216X7R1E105K | TDK ${ }^{(2)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}$, X7R, Ceramic Capacitor, Size 1206 | 2 |
|  | 12063D105MAT | AVX ${ }^{(3)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}$, X7R, Ceramic Capacitor, Size 1206 | 2 |
|  | GRM31MR71H105KA01 | MuRata ${ }^{(4)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}, \mathrm{X} 7 \mathrm{R}$, Ceramic Capacitor, Size 1206 | 2 |
| Q1, Q2 | Si4174DY | Vishay ${ }^{(1)}$ | 30V N-Channel MOSFET | 2 |
| C3, <br> R4, C6, R9, R1, R2, R6, R8 |  |  | Open location - Size 0603 | 0 |
| R5, R7 | CRCW12061001FRT1 | Vishay ${ }^{(1)}$ | 1k ${ }^{\text {R Resistor, Size } 1206}$ | 2 |
| U1 | MIC4223YM | Micrel, Inc. ${ }^{(5)}$ | Dual Inverting 4A MOSFET Driver with SOIC Package | 1 |
| or | MIC4224YM | Micrel, Inc. ${ }^{(5)}$ | Dual Non-Inverting 4A MOSFET Driver with SOIC Package | 1 |
| or | MIC4225YM | Micrel, Inc. ${ }^{(5)}$ | Dual Inverting/Non-Inverting 4A MOSFET Driver with SOIC Package | 1 |

## Notes:

1. Vishay: www.vishay.com
2. TDK: www.tdk.com
3. AVX: www.avx.com
4. MuRata: www.murata.com
5. Micrel, Inc: www.micrel.com

## PCB Layout (SOIC)



## Evaluation Board Schematic (e-PAD MSOP)



## PCB Layout (ePAD MSOP)



## Bill of Materials (ePAD MSOP)

| Item | Part Number | Manufacturer | Description | Qty. |
| :---: | :---: | :---: | :---: | :---: |
| C1 | VJ0603Y104KXXAT | Vishay ${ }^{(1)}$ | 0.1浱25V, X7R Ceramic Capacitor, Size 0603 | 1 |
| $\begin{aligned} & \text { C2, C7 } \\ & \text { or } \\ & \text { or } \end{aligned}$ | C1608X5R1E105M | TDK ${ }^{(2)}$ | 1 $\mu$ F/25V, X5R, Ceramic Capacitor, Size 0603 | 2 |
|  | 06033D105MAT | AVX ${ }^{(3)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}, \mathrm{X} 5 \mathrm{R}$, Ceramic Capacitor, Size 0603 | 2 |
|  | GRM188R61E105KA93 | MuRata ${ }^{(4)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}$, X5R, Ceramic Capacitor, Size 0603 | 2 |
| $\begin{aligned} & \text { C4, C5 } \\ & \text { or } \\ & \text { or } \end{aligned}$ | C3216X7R1E105K | TDK ${ }^{(2)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}, \mathrm{X7R}$, Ceramic Capacitor, Size 1206 | 2 |
|  | 12063D105MAT | AVX ${ }^{(3)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}, \mathrm{X} 7 \mathrm{R}$, Ceramic Capacitor, Size | 2 |
|  | GRM31MR71H105KA01 | MuRata ${ }^{(4)}$ | $1 \mu \mathrm{~F} / 25 \mathrm{~V}, \mathrm{X} 7 \mathrm{R}$, Ceramic Capacitor, Size | 2 |
| C3, <br> R4, <br> C6, <br> R9, <br> R1, <br> R2, <br> R6, R8 |  |  | Open location - Size 0603 | 0 |
| Q1, Q2 | Si4174DY | Vishay ${ }^{(1)}$ | 30V N-Channel MOSFET | 2 |
| R5, R7 | CRCW12061001FRT1 | Vishay ${ }^{(1)}$ | 1k $\Omega$ Resistor, Size 1206 | 2 |
| U1 <br> or or | MIC4223YMME | Micrel, Inc. ${ }^{(5)}$ | Dual Inverting 4A MOSFET Driver with ePAD MSOP Package | 1 |
|  | MIC4224YMME | Micrel, Inc. ${ }^{(5)}$ | Dual Non-Inverting 4A MOSFET Driver with ePAD MSOP Package | 1 |
|  | MIC4225YM | Micrel, Inc. ${ }^{(5)}$ | Dual Inverting/Non-Inverting 4A MOSFET Driver with ePAD MSOP Package | 1 |

Notes:

1. Vishay: www.vishay.com
2. TDK: www.tdk.com
3. AVX: www.avx.com
4. MuRata: www.murata.com
5. Micrel, Inc: www.micrel.com

## Package Information



IDP VIEW


END VIEW


BOTTIM VIEW


DETAIL "A"

NDTES:

1. DIMENSIDNS ARE IN INCHES[MM].
2. CUNTRULLING DIMENSION: INCHES.
3. DIMENSIUN DIES NDT INCLUDE MILD FLASH $\square R$ PROTRUSIONS,

EITHER DF WHICH SHALL NDT EXCEED 0.010[0.25]
PER SIDE.
8-Pin SOIC (M)



DETAIL A

NDTES:
. DIMENSIDNS ARE IN MM [INCHES].
2. CONTRZLLING DIMENSIDN: MM
3. DIMENSIUN DUES NDT INCLUDE MDLD FLASH GR PRUTRUSIONS, EITHER DF WHICH SHALL NQT EXCEED 0.20 [0.008] PER SIDE.

## 8-Pin ePAD MSOP (MME)

MICREL, INC. 2180 FORTUNE DRIVE SAN JOSE, CA 95131 USA
TEL +1 (408) 944-0800 FAX +1 (408) 474-1000 WEB http://www.micrel.com

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